

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/521,068	EZAWA ET AL.	
Examiner		Art Unit		Page 1 of 1
Matthew G. Kayrish		2653		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0062175	04-2004	Inoue, Naoki	369/077.2
*	B	US-2003/0058785	03-2003	Kurosawa, Masashi	369/291
*	C	US-6,477,138	11-2002	Cho et al.	720/742
*	D	US-6,590,858	07-2003	Inoue, Naoki	720/742
*	E	US-5,260,931	11-1993	Sasaki et al.	720/742
*	F	US-4,682,322	07-1987	Ohta, Teruo	720/742
*	G	US-2003/0174640	09-2003	Iwaki et al.	369/291
*	H	US-4,799,121	01-1989	Takahashi, Kenji	360/133
*	I	US-2002/0012316	01-2002	Inoue et al.	369/291
*	J	US-6,480,458	11-2002	Konno et al.	720/644
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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